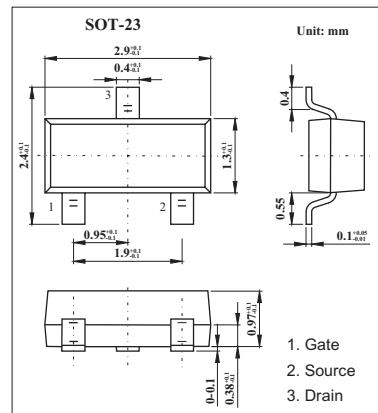
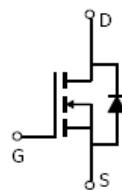


## N-Channel Enhancement Mode Field Effect Transistor

### KO3414(AO3414)

#### ■ Features

- $V_{DS}$  (V) = 20V
- $I_D$  = 4.2A ( $V_{GS}$ =4.5V)
- $R_{DS(ON)} < 50m\Omega$  ( $V_{GS} = 4.5V$ )
- $R_{DS(ON)} < 63m\Omega$  ( $V_{GS} = 2.5V$ )
- $R_{DS(ON)} < 87m\Omega$  ( $V_{GS} = 1.8V$ )



#### ■ Absolute Maximum Ratings $T_A = 25^\circ C$

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	$V_{DS}$	20	V
Gate-Source Voltage	$V_{GS}$	$\pm 8$	V
Continuous Drain Current $T_A=25^\circ C$	$I_D$	4.2	A
Current *1 $T_A=70^\circ C$		3.2	
Pulsed Drain Current *2	$I_{DM}$	15	
Power Dissipation *1 $T_A=25^\circ C$	$P_D$	1.4	W
$T_A=70^\circ C$		0.9	
Thermal Resistance.Junction-to-Ambient *1	$R_{thJA}$	125	$^\circ C/W$
Thermal Resistance.Junction-to-Case	$R_{thJC}$	80	$^\circ C/W$
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	$^\circ C$

\*1The value of  $R_{thJA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz.

Copper, in a still air environment with  $T_A = 25^\circ C$

## KO3414(AO3414)

■ Electrical Characteristics  $T_a = 25^\circ\text{C}$ 

Parameter	Symbol	Testconditons	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	$V_{DSS}$	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	20			V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS}=16\text{V}, V_{GS}=0\text{V}$			1	$\mu\text{A}$
		$V_{DS}=16\text{V}, V_{GS}=0\text{V}, T_J=55^\circ\text{C}$			5	
Gate-Body leakage current	$I_{GSS}$	$V_{DS}=0\text{V}, V_{GS}=\pm 8\text{V}$			$\pm 100$	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	0.4	0.6	1	V
Static Drain-Source On-Resistance	$R_{DS(ON)}$	$V_{GS}=4.5\text{V}, I_D=4.2\text{A}$		41	50	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=4.2\text{A}, T_J=125^\circ\text{C}$		58	70	
		$V_{GS}=2.5\text{V}, I_D=3.7\text{A}$		52	63	
		$V_{GS}=1.8\text{V}, I_D=3.2\text{A}$		67	87	
On state drain current	$I_{D(ON)}$	$V_{GS}=4.5\text{V}, V_{DS}=5\text{V}$	15			A
Forward Transconductance	$g_{FS}$	$V_{DS}=5\text{V}, I_D=4.2\text{A}$		11		S
Input Capacitance	$C_{iss}$	$V_{GS}=0\text{V}, V_{DS}=-10\text{V}, f=1\text{MHz}$		436		pF
Output Capacitance	$C_{oss}$			66		pF
Reverse Transfer Capacitance	$C_{rss}$			44		pF
Gate resistance	$R_g$	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		3		$\Omega$
Total Gate Charge	$Q_g$	$V_{GS}=4.5\text{V}, V_{DS}=-10\text{V}, I_D=4.2\text{A}$		6.2		nC
Gate Source Charge	$Q_{gs}$			1.6		nC
Gate Drain Charge	$Q_{gd}$			0.5		nC
Turn-On DelayTime	$t_{D(on)}$	$V_{GS}=4.5\text{V}, V_{DS}=10\text{V}, R_L=2.7\Omega, R_{GEN}=6\Omega$		5.5		ns
Turn-On Rise Time	$t_r$			6.3		ns
Turn-Off DelayTime	$t_{D(off)}$			40		ns
Turn-Off FallTime	$t_f$			12.7		ns
Body Diode Reverse Recovery Time	$t_{rr}$	$I_F=4\text{A}, dI/dt=100\text{A}/\mu\text{s}$		12.3		ns
Body Diode Reverse Recovery Charge	$Q_{rr}$	$I_F=4\text{A}, dI/dt=100\text{A}/\mu\text{s}$		3.5		nC
Maximum Body-Diode Continuous Current	$I_s$				2	A
Diode Forward Voltage	$V_{SD}$	$I_s=1\text{A}, V_{GS}=0\text{V}$		0.76	1	V